

Special Issue

Applications of Control Systems

Message from the Guest Editor

Applications of control systems have dramatically increased in recent years due to advances in digital processing hardware, yielding faster sampling rates and increased control scheme complexity. In addition, the development of improved sensors and actuators makes practical control systems more feasible. Many publications and conferences are dedicated to the development of control algorithms, but few afford the opportunity to discuss the implementation of control in practical systems. The challenges associated with designing, implementing, and verifying control systems in practical systems are of particular interest. This Special Issue is aimed at providing a platform for subject matter experts in practical control application. It will comprise all areas of control engineering for practical control systems, including system identification, design, implementation, and analysis. This Special Issue may feature applications to mechatronic, robotics, bioengineering, power, aerospace, automotive, and electronic systems, among others. We looking forward to your submission✉

Guest Editor

Dr. Benjamin D. McPheron

School of Science & Engineering, Anderson University

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Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
asi@mdpi.com

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Editor-in-Chief

Prof. Dr. Christos Douligeris
Department of Informatics, University of Piraeus, 18534 Piraeus,
Greece

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